AUTOMOTIVE TEST & MEASUREMENT FEATURE

Achieving Effective Verification and Validation of Vehicle E/E Systems ? Part 5

Thus far, this series has addressed test reuse across workflows, the value of scalable-fidelity in XIL test benches, and generative, model-driven development (MDD) workflow solutions to key verification and validation (V&V) tasks relative to the development of electrical/electronic (E/E) systems in vehicles. Interestingly enough, the solutions to these challenges present another set of brand new challenges, which in turn demand additional solutions.

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performance, improved memory speed and power efficiency.
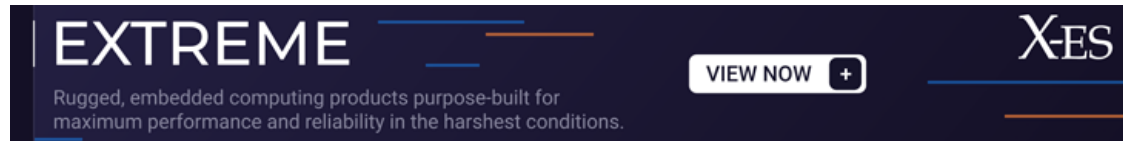
DEVELOPMENT KITS NEWS

STMicroelectronics Enhances STM32G4 MCUs for New Discovery Kits

STMicroelectronics has supplemented its STM32G4 microcontrollers with digital-power and motor-control Discovery Kits, which are supported by new firmware examples in the latest STM32CubeG4 software package (v 1.1.0).

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AUTOMOTIVE IoT NEWS

Excelfore and Microsoft Join Forces on Automotive OTA

Excelfore?s eSync bi-directional data pipeline was migrated to Microsoft Azure for OTA updating and will be included as a Microsoft Connected Vehicle Platform accelerator.

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POWER ELECTRONICS NEWS

EPC and Solace Power to use eGaN FETs in 250W Wireless Power Platforms

The modular platform is based on Equus architecture and enables up to 250 Watts of transmitted power with six degrees of spatial freedom.

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AUTOMOTIVE NETWORKING NEWS

Valens Releases Ultra-High-Speed Automotive Chipset

The VA608A chipset provides data transmission speeds of up to 16Gbps and allows manufacturers to increase native PCIe as a long-distance in-vehicle connectivity technology up to 15m/50ft.

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The Future of IoT is Analog

Most of the innovation in IoT is focused on digital technology. From power servers running software in the cloud, to increasingly more intelligent devices operating ever closer to the edge in our factories, homes and personal devices.
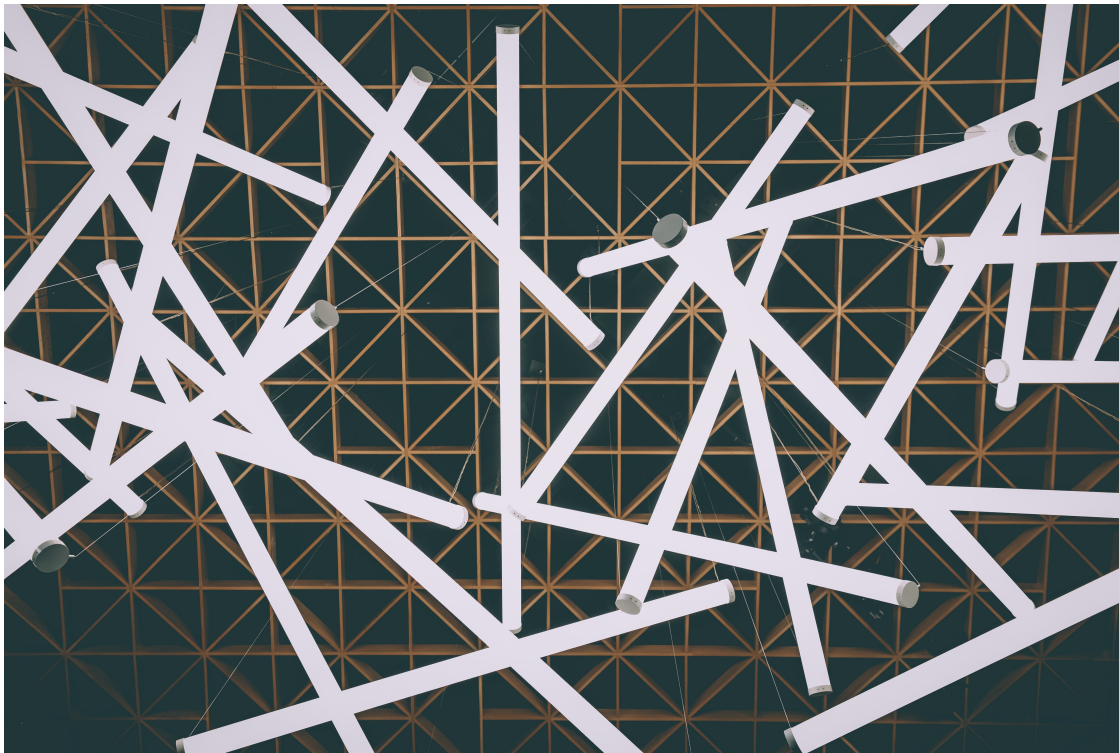
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POWER ELECTRONICS FEATURE

Bus Bars: The 3D Solution to Excessive IR Power-Rail Drop

Voltage drop and low voltage at the load is more than just a nuisance. It can cause circuits to not function at all (not good), or function erratically when the voltage is at the edge of the allowed specification for the various ICs (which is often worse), as the typical rail tolerance window ranges from ?1 percent to ?5 percent, depending on the component. That?s why it?s critical to analyze the drop between power supply and load, and deal with excessive IR drop.

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